


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/039,769	GOULD ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Andrew Hwa S. Lee	2877	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EA 3 5	4/5/05	ahv